

<b>Notice of References Cited</b>	Application/Control No. 10/523,420	Applicant(s)/Patent Under Reexamination LEITE ET AL	
	Examiner H. T. Le	Art Unit 1773	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-4,107,376	08-1978	Ishikawa, Takashi	428/305.5
*	B	US-4,233,199	11-1980	Abolins et al.	524/139
*	C	US-4,254,177	03-1981	Fulmer, Glenn E.	428/305.5
*	D	US-5,721,281	02-1998	Blount, David H.	521/50
*	E	US-5,952,408	09-1999	Lee et al.	524/127
*	F	US-6,160,028	12-2000	Dyer, John Collins	521/64
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.